ROHDE & SCHWARZ Make ideas real



5G-NR COMBINED ACLR/SEM/EVM MEASUREMENT APPLICATION WITH ROHDE & SCHWARZ SPECTRUM ANALYZERS (K147 OPTION)



Key advantages



K147 enables higher testing speeds with multi-threaded calculations based on I/Q data to accelerate ACLR. SEM and EVM measurements.

The challenge of 5G OTA testing

5G OTA tests require a high number of measurements from different angles, meaning long testing times and complex test setups.

Our solution

The K147 option for the R&S[®]FSW and R&S[®]FSV(A)3000 enables combined and automated ACLR, SEM and EVM measurements. Parallel calculations and adaptable trigger settings make the option much faster. This is interesting for over-the-air characterization of devices or component tests that require a large number of measurements.



K147 enables test automation with a customizable trigger concept.

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Feature highlights

- Provides results for entire test series.
- ► Filters results according to user-defined characteristics.
- ► Postprocesses test results in familiar K144 environment.
- ► Stores results for documentation or further analysis.
- K147C supports measurements of multi-component-carrier NR signals.



Various settings available to account for all your measurement requirements

If position and frame triggers are available, they can either be used or options can be selected for highly accurate time triggers, repeating slots and event delays.

In addition, the following settings facilitate your measurements:

- ► Auto gating in ACLR / SEM: automatically measure only in TX on periods for TDD signals
- Sequence auto level: automatically readjust the level setting for each step to account for varying signal power during measurement sequence

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